

First Named Inventor	Kevin G. Donohoe	INFORMATION DISCLOSURE STATEMENT
Serial No.	09/894,460	
Filing Date	June 28, 2001	
Group Art Unit	2825	
Examiner Name	Igwe U. Anya	
Confirmation No.	6410	
Attorney Docket No.	400.100US01	
Title: ETCHING OF HIGH ASPECT RATIO STRUCTURES		

Mail Stop: AMENDMENT
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

In compliance with 37 C.F.R. §§ 1.56 and 1.97, *et seq.*, the enclosed materials are brought to the attention of the Examiner for consideration in connection with the above-identified Application.

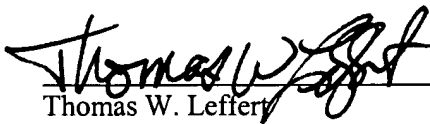
Applicant respectfully requests that this Information Disclosure Statement be entered and the references listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to MPEP §609, Applicant further requests that the Examiner initial next to each reference on the Form 1449 to indicate that the listed references have been considered. Applicant further requests that a copy of the initialed Form 1449 be returned with the next official communication.

As this document is being filed along with an Request for Continued Examination, Applicant believes that no fees are due. However, the Commissioner for Patents is hereby authorized to charge any additional fees to Deposit Account No. 501373.

If the Examiner has any questions or concerns regarding this application, please contact the undersigned at (612) 312-2204.

Respectfully submitted,

Date: 24 Nov 04



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U.S. Patent References				
Examiner Initials	Document No.	Issue/Publication Date	Name	Filing Date
	6,743,727B2	06/01/04	Mathad et al.	06/05/01

Foreign Patent References					
Examiner Initials	Foreign Patent		Name	Publication Date	Translation
	Country	No.			

Other References	
Examiner Initials	Author, Title, Date, Pages, etc.

Examiner Signature		Date Considered	
<small>*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>			